

L Number	Hits	Search Text	DB	Time stamp
-	5078	(two or dual or auxiliary or second) adj4 (ELECTRON ADJ beam\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 15:41
-	223	(two or dual or auxiliary or second) adj4 (ELECTRON ADJ beam\$1) AND SECOND ADJ5 ENERGY	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/22 18:33
-	3750	(electron adj beam) and imag\$3 and (secondary adj electron\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:53
-	2	6038018.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 08:43
-	2	6172363.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 13:41
-	103	electron adj image near3 detector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 14:00
-	4448	250/310 and excess adj3 charge or charge adj (buildup or accululation) or charge adj3 neutraliz\$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 16:51

-	114	(250/310 and excess adj3 charge or charge adj (buildup or accumulation) or charge adj3 neutraliz\$4) and (electron adj beam) and imag\$3 and (secondary adj electron\$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 16:53
-	2	4996434.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 13:11
-	2	5051585.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 13:11
-	0	sem and energy adj filter and band-pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 15:43
-	96	sem and band-pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:49
-	40	sem and band-pass and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:50
-	4	sem and band-pass and image near5 subtract\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:53
-	159	sem and image near5 subtract\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:54

-	73	sem and threshold and image near5 subtract\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/02 15:52
-	4	"6583413"	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/02 15:52
-	3	"6583414"	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/02 18:36
-	0	"6583414".pn. and low near5 energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/02 18:36
-	2	6583414.pn.	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/03 11:17
-	73	(excess adj3 charge or charge adj (buildup or accululation) or charge adj3 neutraliz\$4) and electron adj beam and inspect\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 16:29
-	30	250/310 and (excess adj3 charge or charge adj (buildup or accululation) or charge adj3 neutraliz\$4) and ("low energy" or LEEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/03 13:07
-	4	(two or dual or auxiliary or second) adj4 (source or beam\$1) and parallel adj imaging adj system	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/03 13:16

-	33	electron adj beam and inspect\$3 and charge adj neutraliz\$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:24
-	2	6172363,pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:24
-	1225	(electron adj beam) and imag\$3 and (secondary adj electron\$1) and via	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:53
-	48	(electron adj beam) and imag\$3 and (secondary adj electron\$1) and via and neutralize	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:55
-	14376	(electron adj beam) and energy and via	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:17
-	0	sem and (secondary adj electron near\$3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:18
-	21	sem and (secondary adj electron near\$3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:26
-	21	sem and (secondary adj electron near\$3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:33

-	26	leybourne.xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:39
-	401	(semiconductor or wafer) and via near3 inspect\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:40
-	59	((semiconductor or wafer) and via near3 inspect\$3) and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:40
-	0	sem and energy adj filter and band adj -pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:25
-	5	"5097127"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:15
-	20	"4896036"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:16
-	0	"4896036" and (excess adj3 charge or charge adj (buildup or accululation) or charge adj3 neutraliz\$4) and electron adj beam and inspect\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:30
-	5	"5097127"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:31

-	25	"3896308"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 16:39
-	17	"4896045"	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 16:39
-	593	250/\$.ccls. and sem and (height or depth)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 16:57
-	238	250/\$.ccls. and sem and (height or depth) and charge	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 17:39
-	18	250/\$.ccls. and sem and (height or depth) and charge adj3 (neutralization control buildup)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 16:59
-	51	250/\$.ccls. and sem and (aspect adj ratio) and charge	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/08 17:40
-	4	250/\$.ccls. and sem and (aspect adj ratio) and charge adj3 (neutralization control buildup)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/10 11:34
-	9	250/\$.ccls. and sem and (photons or photo adj electrons) and charge adj3 (neutralization control buildup)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/10 11:56

-	14	250/\$.ccls. and peem	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 11:56
-	411	electron adj beam and photon adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:26
-	4	(electron adj beam and photon adj beam) and energy adj filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:27
-	737	photoelectron and surface near4 charg\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:29
-	164	photoelectron and surface near4 charg\$3 and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:38
-	58	photoelectron and surface adj charg\$3 and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:38
-	2	5493116.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:48
-	2	6232787.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 13:19

-	0	08/892,734.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 13:20
-	0	08892734.pn.	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:03
-	2	photo-emission adj (electron adj microscope)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:09
-	18	photo-emission and (electron adj microscope)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:23
-	116	("Photo Emission Electron Microscope") or (PEEM)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:24
-	11	("Photo Emission Electron Microscope") or (PEEM) and filter	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:32
-	41	("Photo Emission Electron Microscope") or (PEEM) and energy	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 14:32
-	8	electron near threshold adj energy	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT;	2003/12/11 15:50

-	1059	(bandpass or band-pass pr band adj pass) near4 energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:12
-	33	((bandpass or band-pass pr band adj pass) near4 energy) and secondary adj electron\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:03
-	13	((bandpass or band-pass pr band adj pass) near4 energy) and secondary adj electron\$1 and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:10
-	66062	energy near4 (first or second)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:11
-	13276	energy near4 (first or second) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:11
-	104	(bandpass or band-pass pr band adj pass) near4 energy and energy near4 (first or second) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:12
-	2457877	high adj aspect or via or steep adj wall\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:43
-	202	(photon adj beam or laser adj beam) and (photoemission)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:44

-	1383	filter and (scattered adj electron\$1 or secondary adj electrons)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:36
-	5	((high adj aspect or via or steep adj wall\$1) and ((photon adj beam or laser adj beam) and (photoemission))) and (filter and (scattered adj electron\$1 or secondary adj electrons))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:36
-	2448587	250/310 and high adj aspect or via or steep adj wall\$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:43
-	19	250/310 and (photon adj beam or laser adj beam) and (photoemission)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 13:44
-	117	(high adj aspect or via or steep adj wall\$1) and ((photon adj beam or laser adj beam) and (photoemission))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 20:17
-	3	"6583414"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/04/29 20:17
-	1	"4870344".PN.	USPAT	2004/04/29 20:18
-	1	"5085517".PN.	USPAT	2004/04/29 20:20
-	1	"5717204".PN.	USPAT	2004/04/29 20:20
-	1	"5717204".PN.	USPAT	2004/04/29 20:21
-	1	"5777327".PN.	USPAT	2004/04/29 20:22
-	1	"5909276".PN.	USPAT	2004/04/29 20:23
-	1	"6038018".PN.	USPAT	2004/04/29 20:23